

ZXTD4591AM832 MPPS[™] Miniature Package Power Solutions Complementary dual 40V high performance transistor

Summary

NPN Transistor - V_{CEO} = 40V; R_{SAT} = 195m Ω ; I_C = 2.5A PNP Transistor - V_{CEO} = -40V; R_{SAT} = 350m Ω ; I_C = -2A

Description

Packaged in the 3mm x 2mm MLP (Micro Leaded Package), these high performance NPN / PNP combination dual transistors offer lower on state losses making them ideal for use in DC-DC circuits and various driving and power-management functions.

Users will also gain several other key benefits:

- Performance capability equivalent to much larger packages
- Improved circuit efficiency & power levels
- · PCB area and device placement savings
- Lower package height (0.9mm nom)
- · Reduced component count

Features

- Low Saturation Voltage (500mV max @1A)
- H_{FE} specified up to 2A
- I_C = 2.5A Continuous Collector Current
- 3mm x 2mm MLP

Applications

- DC DC Converters
- · Power switches
- Motor control
- LED Backlighting circuits

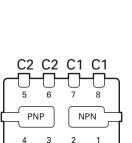
Ordering information

Device	Reel size (inches)	Tape width (mm)	Quantity per reel
ZXTD4591AM832TA	7	8	3,000
ZXTD4591AM832TC	13	8	10,000

Device marking

91A

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C2

E2

C1

E1

B2

B1

Bottom view

B1

E2 B2 E1



Absolute maximum ratings

Parameter	Symbol	NPN	PNP	Unit
Collector-Base voltage	V _{CBO}	40	-40	V
Collector-Emitter voltage	V _{CEO}	40	-40	V
Emitter-Base voltage	V _{EBO}	5	-5	V
Peak pulse current	I _{CM}	3	-3	A
Continuous collector current ^{(a)(f)}	I _C	2	-1.5	A
Continuous collector current ^{(b)(f)}	Ι _C	2.5	-2.0	A
Base current	I _B	30	00	mA
Power dissipation at $T_A = 25^{\circ}C^{(a)(f)}$	P _D	1.	.5	W
Linear derating factor		1	mW/°C	
Power dissipation at $T_A = 25^{\circ}C^{(b)(f)}$	P _D	2.45		W
Linear derating factor		19.6		mW/°C
Power dissipation at $T_A = 25^{\circ}C^{(c)(f)}$	P _D	2 _D 1		W
Linear derating factor		8	mW/°C	
Power dissipation at $T_A = 25^{\circ}C^{(d)(f)}$	PD	1.13		W
Linear derating factor		9		mW/°C
Power dissipation at $T_A = 25^{\circ}C^{(d)(g)}$	PD	1.7		W
Linear derating factor		13.6		mW/°C
Power dissipation at $T_A = 25^{\circ}C^{(e)(g)}$	PD	3		W
Linear derating factor		24		mW/°C
Storage temperature range	T _{stg}	-55 to +150		°C
Junction temperature range	Tj	15	50	°C

Thermal resistance

Parameter	Symbol	Value	Unit
Junction to ambient ^{(a)(f)}	R _{θJA}	83.3	°C/W
Junction to ambient ^{(b)(f)}	R _{0JA}	51	°C/W
Junction to ambient ^{(c)(f)}	R _{0JA}	125	°C/W
Junction to ambient ^{(d)(f)}	R _{0JA}	111	°C/W
Junction to ambient ^{(d)(g)}	R _{0JA}	73.5	°C/W
Junction to ambient ^{(e)(g)}	R _{0JA}	41.7	°C/W

NOTES:

(a) For a dual device surface mounted on 8 sq cm single sided 2oz copper on FR4 PCB, in still air conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device. (b) Measured at t<5 secs for a dual device surface mounted on 8 sq cm single sided 2oz copper on FR4 PCB, in still air

conditions with all exposed pads attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.

(c) For a dual device surface mounted on 8 sq cm single sided 2oz copper on FR4 PCB, in still air conditions with minimal lead connections only.

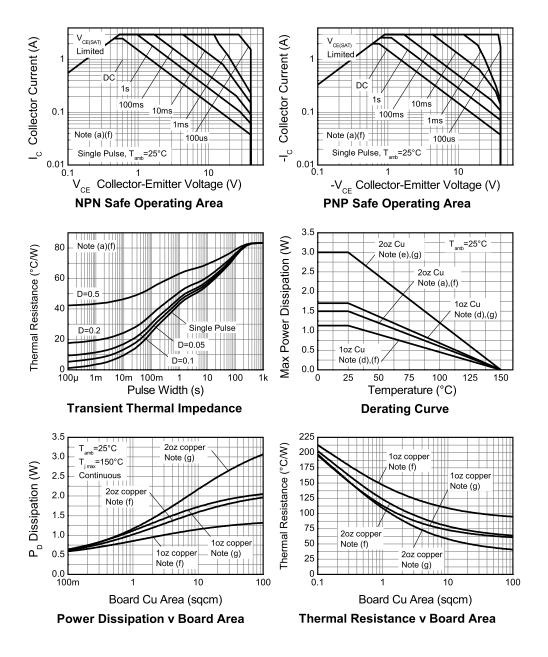
(d) For a dual device surface mounted on 10 sq cm single sided 1oz copper on FR4 PCB, in still air conditions with all exposed pads attached attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.

(e) For a dual device surface mounted on 85 sq cm single sided 2oz copper on FR4 PCB, in still air conditions with all exposed pads attached attached. The copper area is split down the centre line into two separate areas with one half connected to each half of the dual device.

(f) For a dual device with one active die. (g) For dual device with 2 active die running at equal power.

(h) Repetitive rating - pulse width limited by max junction temperature. Refer to Transient Thermal Impedance graph.
(i) The minimum copper dimensions required for mounting are no smaller than the exposed metal pads on the base of the device as shown in the package dimensions data. The thermal resistance for a dual device mounted on 1.5mm thick FR4 board using minimum copper 1 oz weight, 1mm wide tracks and one half of the device active is Rth = 250°C/W giving a power rating of Ptot = 500mW. (i)

Typical characteristics



NPN Transistor

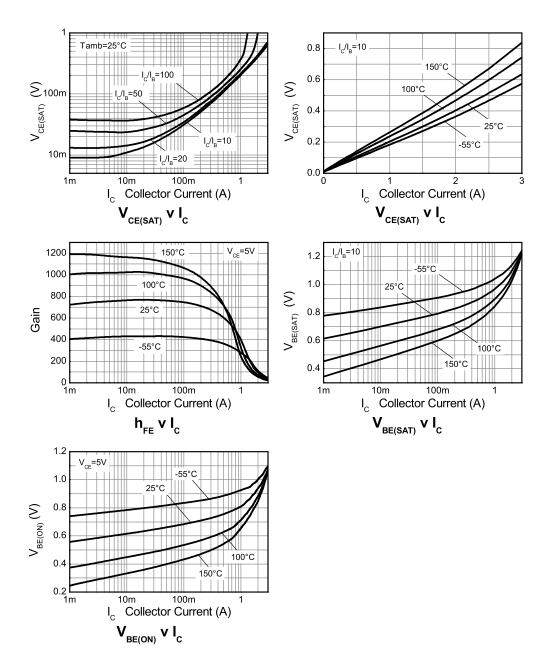
Electrical characteristics (at $T_{amb} = 25^{\circ}C$ unless otherwise stated).

Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Collector-Base	V _{(BR)CBO}	40			V	I _C = 100μA
breakdown voltage						
Collector-Emitter	V _{(BR)CEO}	40			V	l _C = 10mA ^(*)
breakdown voltage						
Emitter-Base	V _{(BR)EBO}	5			V	I _E = 100μA
breakdown voltage						
Collector cut-off	I _{CBO}			100	nA	V _{CB} =30V
current						
Emitter cut-off current	I _{EBO}			100	nA	$V_{EB} = 4V$
Collector Emitter cut-	I _{CES}			100	nV	V _{CE} = 30V
off current						
Collector Emitter	V _{CE(sat)}			300	mV	l _C = 0.5A, l _B = 50mA ^(*)
saturation voltage				500	mV	I _C = 1A, I _B = 100mA ^(*)
Base-Emitter	V _{BE(sat)}			1.1	V	I _C = 1A, I _B = 100mA ^(*)
saturation voltage						
Base-Emitter turn-on	V _{BE(on)}			1.0	V	$I_{C} = 1A, V_{CE} = 5V^{(*)}$
voltage						
Static forward current	h _{FE}	300				$I_{C} = 1mA, V_{CE} = 5V^{(*)}$
transfer ratio		300		900		$I_{C} = 0.5A, V_{CE} = 5V^{(*)}$
		200				$I_{C} = 1A, V_{CE} = 5V^{(*)}$
		35				$I_{C} = 2A, V_{CE} = 5V^{(*)}$
Transition frequency	f _T	150			MHz	I _C = -50mA, V _{CE} = -10V
						f = 100MHz
Output capacitance	C _{OBO}			10	pF	V _{CB} = -10V, f = 1MHz

NOTES:

(*) Measured under pulsed conditions.

NPN Typical characteristics



PNP Transistor

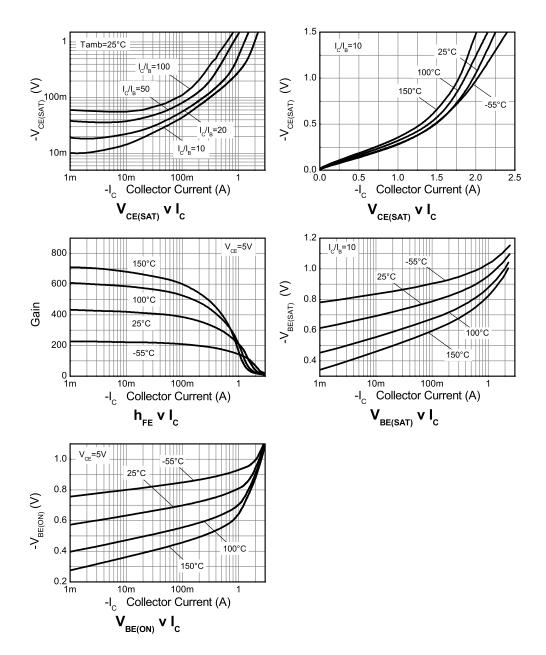
Electrical characteristics (at $T_{amb} = 25^{\circ}C$ unless otherwise stated).

Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Collector-Base	V _{(BR)CBO}	-40	. 76.		V	I _C = -100μA
breakdown voltage	• (BR)CBU	10				
Collector-Emitter	V _{(BR)CEO}	-40			V	I _C = -10mA ^(*)
breakdown voltage	(BII)CLO					
Emitter-Base	V _{(BR)EBO}	-5			V	I _F = -100μA
breakdown voltage	(811)280					
Collector cut-off	I _{CBO}			-100	nA	V _{CB} = -30V
current						
Emitter cut-off current	I _{EBO}			-100	nA	$V_{EB} = -4V$
Collector Emitter cut-	I _{CES}			-100	nV	V _{CE} = -30V
off current						
Collector Emitter	V _{CE(sat)}			-200	mV	I _C = -0.1A, I _B = -1mA ^(*)
saturation voltage				-350	mV	I _C = -0.5A, I _B = -20mA ^(*)
				-500	mV	I _C = -1A, I _B = -100mA ^(*)
Base-Emitter	V _{BE(sat)}			-1.1	V	I _C = -1A, I _B = -50mA ^(*)
saturation voltage						
Base-Emitter turn-on	V _{BE(on)}			-1.0	V	$I_{C} = -1A, V_{CE} = -5V^{(*)}$
voltage						
Static forward current	h _{FE}	300				I _C = -1mA, V _{CE} = -5V ^(*)
transfer ratio		300		800		I _C = -0.1A, V _{CE} = -5V ^(*)
		250				$I_{C} = -0.5A, V_{CE} = -5V^{(*)}$
		160				$I_{\rm C} = -1$ A, $V_{\rm CE} = -5V^{(*)}$
		30				$I_{\rm C} = -2A, V_{\rm CE} = -5V^{(*)}$
Transition frequency	f _T	150			MHz	I _C = -50mA, V _{CE} = -10V
						f = 100MHz
Output capacitance	C _{OBO}			10	pF	V _{CB} = -10V, f = 1MHz

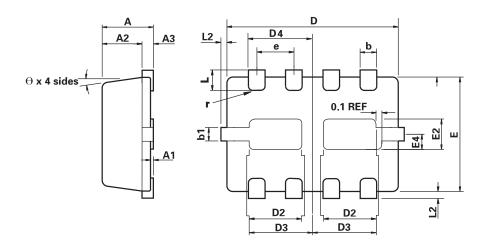
NOTES:

(*) Measured under pulsed conditions.

PNP electrical characteristics



Package outline MLP832



Dim.	Millin	Millimeters		Inches		Millin	neters	Inc	hes	
Dini.	Min.	Max.	Min.	Max.	Dim.	Min.	Max.	Min.	Max.	
А	0.80	1.00	0.0315	0.0394	е	0.65 BSC		0.0256 BSC		
A1	0.00	0.05	0.00	0.002	E	2.00	2.00 BSC		0.0787 BSC	
A2	0.65	0.75	0.0256	0.0295	E2	0.43	0.63	0.017	0.0248	
A3	0.15	0.25	0.006	0.0098	E4	0.16	0.36	0.006	0.014	
b	0.24	0.34	0.0095	0.0134	L	0.20	0.45	0.0079	0.0177	
b1	0.17	0.30	0.0068	0.0118	L2	0.00	0.125	0.00	0.005	
D	3.00	BSC	0.118 BSC		r	0.075	BSC	0.002	9 BSC	
D2	0.82	1.02	0.0323	0.0402	θ	0°	12°	0°	12°	
D3	1.01	1.21	0.0398	0.0476	-	-	-	-	-	

Note: Controlling dimensions are in millimeters. Approximate dimensions are provided in inches

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Zetex sales offices

Europe	Americas	Asia Pacific	Corporate Headquarters
Zetex GmbH Kustermann-Park Balanstraße 59 D-81541 München Germanv	Zetex Inc 700 Veterans Memorial Highway Hauppauge, NY 11788 USA	Zetex (Asia Ltd) 3701-04 Metroplaza Tower 1 Hing Fong Road, Kwai Fong Hong Kong	Zetex Semiconductors plc Zetex Technology Park, Chadderton Oldham, OL9 9LL United Kingdom
Telefon: (49) 89 45 49 49 0 Fax: (49) 89 45 49 49 49 europe.sales@zetex.com	Telephone: (1) 631 360 2222 Fax: (1) 631 360 8222 usa.sales@zetex.com	Telephone: (852) 26100 611 Fax: (852) 24250 494 asia.sales@zetex.com	Telephone: (44) 161 622 4444 Fax: (44) 161 622 4446 hq@zetex.com

© 2008 Published by Zetex Semiconductors plc

Issue 2 - April 2008

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